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	Abstract: Increasingly, system-on-a-chip (SOC) designers are looking to leverage the ex design service providers to bring products to market. Design service providers engaged at various points in the design process: from design conception and sp to processing a completed technology dependent netlist. Engagement typically stage intermediate to these points; completed RTL for some portion of the desi exist but assistance is needed to integrate the RTL with other core IF, or design may be enlisted to develop some portion of the RTL or new cores to perform sp functions. Proper management of RTL design source is critical to the overall suc project. This paper describes a methodology used by a design service provider this issue.
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